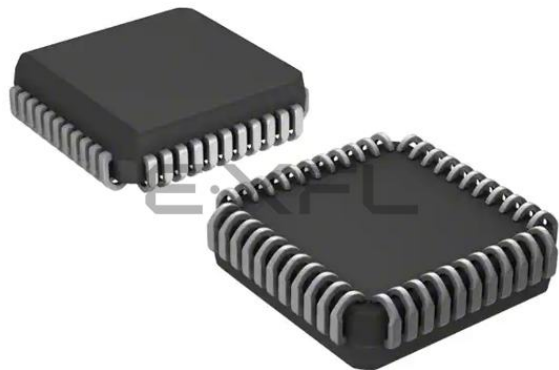




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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	34
Number of Gates	6000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	44-LCC (J-Lead)
Supplier Device Package	44-PLCC (16.59x16.59)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a40mx04-3plg44



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2.4 Plastic Device Resources

Table 2 • Plastic Device Resources

Device	User I/Os											
	PLCC 44-Pin	PLCC 68-Pin	PLCC 84-Pin	PQFP 100-Pin	PQFP 144-Pin	PQFP 160-Pin	PQFP 208-Pin	PQFP 240-Pin	VQFP 80-Pin	VQFP 100-Pin	TQFP 176-Pin	PBGA 272-Pin
A40MX02	34	57	–	57	–	–	–	–	57	–	–	–
A40MX04	34	57	69	69	–	–	–	–	69	–	–	–
A42MX09	–	–	72	83	95	101	–	–	–	83	104	–
A42MX16	–	–	72	83	–	125	140	–	–	83	140	–
A42MX24	–	–	72	–	–	125	176	–	–	–	150	–
A42MX36	–	–	–	–	–	–	176	202	–	–	–	202

Note: Package Definitions: PLCC = Plastic Leaded Chip Carrier, PQFP = Plastic Quad Flat Pack, TQFP = Thin Quad Flat Pack, VQFP = Very Thin Quad Flat Pack, PBGA = Plastic Ball Grid Array

2.5 Ceramic Device Resources

Table 3 • Ceramic Device Resources

Device	User I/Os			
	CPGA 132-Pin	CQFP 172-Pin	CQFP 208-Pin	CQFP 256-Pin
A42MX09	95			
A42MX16		131		
A42MX36			176	202

Note: Package Definitions: CQFP = Ceramic Quad Flat Pack

2.6 Temperature Grade Offerings

Table 4 • Temperature Grade Offerings

Package	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
PLCC 44	C, I, M	C, I, M				
PLCC 68	C, I, A, M	C, I, M				
PLCC 84		C, I, A, M	C, I, A, M	C, I, M	C, I, M	
PQFP 100	C, I, A, M	C, I, A, M	C, I, A, M	C, I, M		
PQFP 144			C			
PQFP 160			C, I, A, M	C, I, M	C, I, A, M	
PQFP 208				C, I, A, M	C, I, A, M	C, I, A, M
PQFP 240						C, I, A, M
VQFP 80	C, I, A, M	C, I, A, M				
VQFP 100			C, I, A, M	C, I, A, M		
TQFP 176			C, I, A, M	C, I, A, M	C, I, A, M	
PBGA 272						C, I, M
CQFP 172				C, M, B		
CQFP 208						C, M, B
CQFP 256						C, M, B
CPGA 132			C, M, B			

Note: C = Commercial
 I = Industrial
 A = Automotive
 M = Military
 B = MIL-STD-883 Class B

2.7 Speed Grade Offerings

Table 5 • Speed Grade Offerings

	– F	Std	–1	–2	–3
C	P	P	P	P	P
I		P	P	P	P
A		P			
M		P	P		
B		P	P		

Note: See the [40MX and 42MX Automotive Family FPGAs](#) datasheet for details on automotive-grade MX offerings.

Contact your local [Microsemi Sales representative](#) for device availability.

3.8.1 3.3 V LVTTTL Electrical Specifications

Table 19 • 3.3V LVTTTL Electrical Specifications

Symbol	Parameter	Commercial		Commercial -F		Industrial		Military		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
VOH ¹	IOH = -4 mA	2.15		2.15		2.4		2.4		V
VOL ¹	IOL = 6 mA		0.4		0.4		0.48		0.48	V
VIL		-0.3	0.8	-0.3	0.8	-0.3	0.8	-0.3	0.8	V
VIH (40MX)		2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	V
VIH (42MX)		2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	V
IIL			-10		-10		-10		-10	μA
IIH			-10		-10		-10		-10	μA
Input Transition Time, T _R and T _F			500		500		500		500	ns
C _{IO} I/O Capacitance			10		10		10		10	pF
Standby Current, ICC ²	A40MX02, A40MX04		3		25		10		25	mA
	A42MX09		5		25		25		25	mA
	A42MX16		6		25		25		25	mA
	A42MX24, A42MX36		15		25		25		25	mA
Low-Power Mode Standby Current	42MX devices only		0.5		ICC - 5.0		ICC - 5.0		ICC - 5.0	mA
IIO, I/O source sink current	Can be derived from the <i>IBIS model</i> (http://www.microsemi.com/soc/techdocs/models/ibis.html)									

1. Only one output tested at a time. VCC/VCCI = min.
2. All outputs unloaded. All inputs = VCC/VCCI or GND.

3.9 Mixed 5.0 V / 3.3 V Operating Conditions (for 42MX Devices Only)

Table 20 • Absolute Maximum Ratings*

Symbol	Parameter	Limits	Units
VCCI	DC Supply Voltage for I/Os	-0.5 to +7.0	V
VCCA	DC Supply Voltage for Array	-0.5 to +7.0	V
VI	Input Voltage	-0.5 to VCCA + 0.5	V
VO	Output Voltage	-0.5 to VCCI + 0.5	V
t _{STG}	Storage Temperature	-65 to +150	°C

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device

Table 35 • A40MX02 Timing Characteristics (Nominal 3.3 V Operation) (continued)
(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{RD1}	FO = 1 Routing Delay		2.0		2.2		2.5		3.0		4.2	ns
t _{RD2}	FO = 2 Routing Delay		2.7		3.1		3.5		4.1		5.7	ns
t _{RD3}	FO = 3 Routing Delay		3.4		3.9		4.4		5.2		7.3	ns
t _{RD4}	FO = 4 Routing Delay		4.2		4.8		5.4		6.3		8.9	ns
t _{RD8}	FO = 8 Routing Delay		7.1		8.2		9.2		10.9		15.2	ns
Logic Module Sequential Timing²												
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up		4.3		4.9		5.6		6.6		9.2	ns
t _{HD} ³	Flip-Flop (Latch) Data Input Hold		0.0		0.0		0.0		0.0		0.0	ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up		4.3		4.9		5.6		6.6		9.2	ns
t _{HENA}	Flip-Flop (Latch) Enable Hold		0.0		0.0		0.0		0.0		0.0	ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		4.6		5.3		6.0		7.0		9.8	ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		4.6		5.3		6.0		7.0		9.8	ns
t _A	Flip-Flop Clock Input Period		6.8		7.8		8.9		10.4		14.6	ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency (FO = 128)		109		101		92		80		48	MHz
Input Module Propagation Delays												
t _{INYH}	Pad-to-Y HIGH		1.0		1.1		1.3		1.5		2.1	ns
t _{INYL}	Pad-to-Y LOW		0.9		1.0		1.1		1.3		1.9	ns
Input Module Predicted Routing Delays¹												
t _{IRD1}	FO = 1 Routing Delay		2.9		3.4		3.8		4.5		6.3	ns
t _{IRD2}	FO = 2 Routing Delay		3.6		4.2		4.8		5.6		7.8	ns
t _{IRD3}	FO = 3 Routing Delay		4.4		5.0		5.7		6.7		9.4	ns
t _{IRD4}	FO = 4 Routing Delay		5.1		5.9		6.7		7.8		11.0	ns
t _{IRD8}	FO = 8 Routing Delay		8.0		9.26		10.5		12.6		17.3	ns
Global Clock Network												
t _{CKH}	Input LOW to HIGH	FO = 16	6.4		7.4		8.3		9.8		13.7	ns
		FO = 128	6.4		7.4		8.3		9.8		13.7	
t _{CKL}	Input HIGH to LOW	FO = 16	6.7		7.8		8.8		10.4		14.5	ns
		FO = 128	6.7		7.8		8.8		10.4		14.5	
t _{PWH}	Minimum Pulse Width HIGH	FO = 16	3.1		3.6		4.1		4.8		6.7	ns
		FO = 128	3.3		3.8		4.3		5.1		7.1	
t _{PWL}	Minimum Pulse Width LOW	FO = 16	3.1		3.6		4.1		4.8		6.7	ns
		FO = 128	3.3		3.8		4.3		5.1		7.1	
t _{CKSW}	Maximum Skew	FO = 16	0.6		0.6		0.7		0.8		1.2	ns
		FO = 128	0.8		0.9		1.0		1.2		1.6	

Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	4.6		5.3		5.6		7.0		9.8		ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.6		5.3		5.6		7.0		9.8		ns
t _A	Flip-Flop Clock Input Period	6.8		7.8		8.9		10.4		14.6		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency (FO = 128)		109		101		92		80		48	MHz
Input Module Propagation Delays												
t _{INYH}	Pad-to-Y HIGH		1.0		1.1		1.3		1.5		2.1	ns
t _{INYL}	Pad-to-Y LOW		0.9		1.0		1.1		1.3		1.9	ns

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		2.4		2.7		3.1		3.6		5.1	ns
t _{DHL}	Data-to-Pad LOW		2.9		3.2		3.6		4.3		6.0	ns
t _{ENZH}	Enable Pad Z to HIGH		2.7		2.9		3.3		3.9		5.5	ns
t _{ENZL}	Enable Pad Z to LOW		2.9		3.2		3.7		4.3		6.1	ns
t _{ENHZ}	Enable Pad HIGH to Z		4.9		5.4		6.2		7.3		10.2	ns
t _{ENLZ}	Enable Pad LOW to Z		5.3		5.9		6.7		7.9		11.1	ns
t _{GLH}	G-to-Pad HIGH		4.2		4.6		5.2		6.1		8.6	ns
t _{GHL}	G-to-Pad LOW		4.2		4.6		5.2		6.1		8.6	ns
t _{LSU}	I/O Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t _{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		5.2		5.8		6.6		7.7		10.8	ns
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		7.4		8.2		9.3		10.9		15.3	ns
d _{TLH}	Capacity Loading, LOW to HIGH		0.03		0.03		0.03		0.04		0.06	ns/pF
d _{THL}	Capacity Loading, HIGH to LOW		0.04		0.04		0.04		0.05		0.07	ns/pF

1. For dual-module macros, use t_{PD1} + t_{RD1} + t_{PDn}, t_{CO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading

Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays ¹												
t _{PD1}	Single Module		1.6		1.8		2.1		2.5		3.5	ns
t _{CO}	Sequential Clock-to-Q		1.8		2.0		2.3		2.7		3.8	ns
t _{GO}	Latch G-to-Q		1.7		1.9		2.1		2.5		3.5	ns
t _{RS}	Flip-Flop (Latch) Reset-to-Q		2.0		2.2		2.5		2.9		4.1	ns
Logic Module Predicted Routing Delays ²												
t _{RD1}	FO = 1 Routing Delay		1.0		1.1		1.2		1.4		2.0	ns
t _{RD2}	FO = 2 Routing Delay		1.3		1.4		1.6		1.9		2.7	ns
t _{RD3}	FO = 3 Routing Delay		1.6		1.8		2.0		2.4		3.3	ns

Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description			-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Propagation Delays													
t _{INYH}	Pad-to-Y HIGH		1.5		1.6		1.8		2.17		3.0		ns
t _{INYL}	Pad-to-Y LOW		1.2		1.3		1.4		1.7		2.4		ns
t _{INGH}	G to Y HIGH		1.8		2.0		2.3		2.7		3.7		ns
t _{INGL}	G to Y LOW		1.8		2.0		2.3		2.7		3.7		ns
Input Module Predicted Routing Delays ²													
t _{IRD1}	FO = 1 Routing Delay		2.8		3.2		3.6		4.2		5.9		ns
t _{IRD2}	FO = 2 Routing Delay		3.2		3.5		4.0		4.7		6.6		ns
t _{IRD3}	FO = 3 Routing Delay		3.5		3.9		4.4		5.2		7.3		ns
t _{IRD4}	FO = 4 Routing Delay		3.9		4.3		4.9		5.7		8.0		ns
t _{IRD8}	FO = 8 Routing Delay		5.2		5.8		6.6		7.7		10.8		ns
Global Clock Network													
t _{CKH}	Input LOW to HIGH	FO = 32	4.1		4.5		5.1		6.0		8.4		ns
		FO = 256	4.5		5.0		5.6		6.7		9.3		ns
t _{CKL}	Input HIGH to LOW	FO = 32	5.0		5.5		6.2		7.3		10.2		ns
		FO = 256	5.4		6.0		6.8		8.0		11.2		ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	1.7		1.9		2.1		2.5		3.5		ns
		FO = 256	1.9		2.1		2.3		2.7		3.8		ns
t _{PWL}	Minimum Pulse Width LOW	FO = 32	1.7		1.9		2.1		2.5		3.5		ns
		FO = 256	1.9		2.1		2.3		2.7		3.8		ns
t _{CKSW}	Maximum Skew	FO = 32	0.4		0.5		0.5		0.6		0.9		ns
		FO = 256	0.4		0.5		0.5		0.6		0.9		ns
t _{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 256	0.0		0.0		0.0		0.0		0.0		ns
t _{HEXT}	Input Latch External Hold	FO = 32	3.3		3.7		4.2		4.9		6.9		ns
		FO = 256	3.7		4.1		4.6		5.5		7.6		ns
t _P	Minimum Period	FO = 32	5.6		6.2		6.7		7.8		12.9		ns
		FO = 256	6.1		6.8		7.4		8.5		14.2		ns
f _{MAX}	Maximum Frequency	FO = 32	177		161		148		129		77		MHz
		FO = 256	161		146		135		117		70		MHz

Table 41 • A42MX16 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Sequential Timing ^{3, 4}													
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up		0.5		0.5		0.6		0.7		0.9		ns
t _{HD}	Flip-Flop (Latch) Data Input Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up		1.0		1.1		1.2		1.4		2.0		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		4.8		5.3		6.0		7.1		9.9		ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		6.2		6.9		7.9		9.2		12.9		ns
t _A	Flip-Flop Clock Input Period		9.5		10.6		12.0		14.1		19.8		ns
t _{INH}	Input Buffer Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input Buffer Latch Set-Up		0.7		0.8		0.9		1.01		1.4		ns
t _{OUTH}	Output Buffer Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{OUTSU}	Output Buffer Latch Set-Up		0.7		0.8		0.89		1.01		1.4		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency			129		117		108		94		56	MHz
Input Module Propagation Delays													
t _{INYH}	Pad-to-Y HIGH			1.5		1.6		1.9		2.2		3.1	ns
t _{INYL}	Pad-to-Y LOW			1.1		1.3		1.4		1.7		2.4	ns
t _{INGH}	G to Y HIGH			2.0		2.2		2.5		2.9		4.1	ns
t _{INGL}	G to Y LOW			2.0		2.2		2.5		2.9		4.1	ns
Input Module Predicted Routing Delays ²													
t _{IRD1}	FO = 1 Routing Delay			2.6		2.9		3.2		3.8		5.3	ns
t _{IRD2}	FO = 2 Routing Delay			2.9		3.2		3.7		4.3		6.1	ns
t _{IRD3}	FO = 3 Routing Delay			3.3		3.6		4.1		4.9		6.8	ns
t _{IRD4}	FO = 4 Routing Delay			3.6		4.0		4.6		5.4		7.6	ns
t _{IRD8}	FO = 8 Routing Delay			5.1		5.6		6.4		7.5		10.5	ns
Global Clock Network													
t _{CKH}	Input LOW to HIGH	FO = 32	4.4		4.8		5.5		6.5		9.0	ns	
		FO = 384	4.8		5.3		6.0		7.1		9.9	ns	
t _{CKL}	Input HIGH to LOW	FO = 32	5.3		5.9		6.7		7.8		11.0	ns	
		FO = 384	6.2		6.9		7.9		9.2		12.9	ns	
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	5.7		6.3		7.1		8.4		11.8	ns	
		FO = 384	6.6		7.4		8.3		9.8		13.7	ns	

Table 42 • A42MX24 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		2.4		2.7		3.1		3.6		5.1	ns
t _{DHL}	Data-to-Pad LOW		2.8		3.2		3.6		4.2		5.9	ns
t _{ENZH}	Enable Pad Z to HIGH		2.5		2.8		3.2		3.8		5.3	ns
t _{ENZL}	Enable Pad Z to LOW		2.8		3.1		3.5		4.2		5.9	ns
t _{ENHZ}	Enable Pad HIGH to Z		5.2		5.7		6.5		7.6		10.7	ns
t _{ENLZ}	Enable Pad LOW to Z		4.8		5.3		6.0		7.1		9.9	ns
t _{GLH}	G-to-Pad HIGH		2.9		3.2		3.6		4.3		6.0	ns
t _{GHL}	G-to-Pad LOW		2.9		3.2		3.6		4.3		6.0	ns
t _{LSU}	I/O Latch Output Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t _{LH}	I/O Latch Output Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.6		6.1		6.9		8.1		11.4	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		10.6		11.8		13.4		15.7		22.0	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.04		0.04		0.04		0.05		0.07	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW		0.03		0.03		0.03		0.04		0.06	ns/pF

Table 44 • A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		3.5		3.9		4.5		5.2		7.3	ns
t _{DHL}	Data-to-Pad LOW		2.5		2.7		3.1		3.6		5.1	ns
t _{ENZH}	Enable Pad Z to HIGH		2.7		3.0		3.3		3.9		5.5	ns
t _{ENZL}	Enable Pad Z to LOW		2.9		3.3		3.7		4.3		6.1	ns
t _{ENHZ}	Enable Pad HIGH to Z		5.3		5.8		6.6		7.8		10.9	ns
t _{ENLZ}	Enable Pad LOW to Z		4.9		5.5		6.2		7.3		10.2	ns
t _{GLH}	G-to-Pad HIGH		5.0		5.6		6.3		7.5		10.4	ns
t _{GHL}	G-to-Pad LOW		5.0		5.6		6.3		7.5		10.4	ns
t _{LSU}	I/O Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t _{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.7		6.3		7.1		8.4		11.8	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.8		8.6		9.8		11.5		16.1	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.07		0.08		0.09		0.10		0.14	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW		0.07		0.08		0.09		0.10		0.14	ns/pF

1. For dual-module macros, use t_{PD1} + t_{RD1} + t_{PDn}, t_{CO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Combinatorial Functions ¹												
t _{PD}	Internal Array Module Delay		1.9		2.1		2.3		2.7		3.8	ns
t _{PDD}	Internal Decode Module Delay		2.2		2.5		2.8		3.3		4.7	ns
Logic Module Predicted Routing Delays ²												
t _{RD1}	FO = 1 Routing Delay		1.3		1.5		1.7		2.0		2.7	ns
t _{RD2}	FO = 2 Routing Delay		1.8		2.0		2.3		2.7		3.7	ns
t _{RD3}	FO = 3 Routing Delay		2.3		2.5		2.8		3.4		4.7	ns
t _{RD4}	FO = 4 Routing Delay		2.8		3.1		3.5		4.1		5.7	ns

Input, output, tristate or bidirectional buffer. Input and output levels are compatible with standard TTL and CMOS specifications. Unused I/Os pins are configured by the Designer software as shown in [Table 46](#), page 84.

Table 46 • Configuration of Unused I/Os

Device	Configuration
A40MX02, A40MX04	Pulled LOW
A42MX09, A42MX16	Pulled LOW
A42MX24, A42MX36	Tristated

In all cases, it is recommended to tie all unused MX I/O pins to LOW on the board. This applies to all dual-purpose pins when configured as I/Os as well.

LP, Low Power Mode

Controls the low power mode of all 42MX devices. The device is placed in the low power mode by connecting the LP pin to logic HIGH. In low power mode, all I/Os are tristated, all input buffers are turned OFF, and the core of the device is turned OFF. To exit the low power mode, the LP pin must be set LOW. The device enters the low power mode 800 ns after the LP pin is driven to a logic HIGH. It will resume normal operation in 200 μ s after the LP pin is driven to a logic LOW.

MODE, Mode

Controls the use of multifunction pins (DCLK, PRA, PRB, SDI, TDO). The MODE pin is held HIGH to provide verification capability. The MODE pin should be terminated to GND through a 10k Ω resistor so that the MODE pin can be pulled HIGH when required.

NC, No Connection

This pin is not connected to circuitry within the device. These pins can be driven to any voltage or can be left floating with no effect on the operation of the device.

PRA, I/O

PRB, I/OProbe A/B

The Probe pin is used to output data from any user-defined design node within the device. Each diagnostic pin can be used in conjunction with the other probe pin to allow real-time diagnostic output of any signal path within the device. The Probe pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. The Probe pin is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

QCLKA/B/C/D, I/O Quadrant Clock

Quadrant clock inputs for A42MX36 devices. When not used as a register control signal, these pins can function as user I/Os.

SDI, I/O Serial Data Input

Serial data input for diagnostic probe and device programming. SDI is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

SDO, I/O Serial Data Output

Serial data output for diagnostic probe and device programming. SDO is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW. SDO is available for 42MX devices only.

When Silicon Explorer II is being used, SDO will act as an output while the "checksum" command is run. It will return to user I/O when "checksum" is complete.

TCK, I/O Test Clock

Figure 39 • PL68

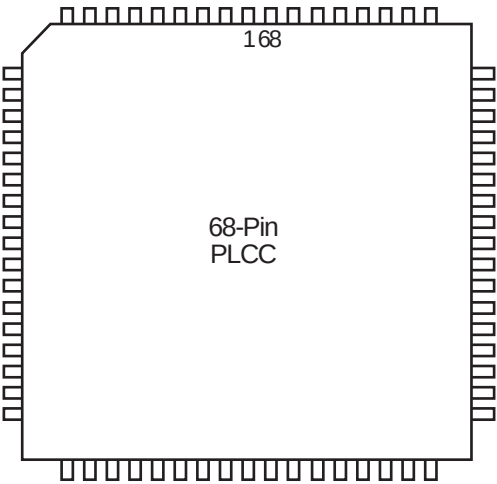


Table 48 • PL68

PL68		
Pin Number	A40MX02 Function	A40MX04 Function
1	I/O	I/O
2	I/O	I/O
3	I/O	I/O
4	VCC	VCC
5	I/O	I/O
6	I/O	I/O
7	I/O	I/O
8	I/O	I/O
9	I/O	I/O
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	GND	GND
15	GND	GND
16	I/O	I/O
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	I/O	I/O
21	VCC	VCC
22	I/O	I/O
23	I/O	I/O

Table 51 • PQ144

PQ144	
Pin Number	A42MX09 Function
80	GNDI
81	NC
82	I/O
83	I/O
84	I/O
85	I/O
86	I/O
87	I/O
88	VKS
89	VPP
90	VCC
91	VCCI
92	NC
93	VSV
94	I/O
95	I/O
96	I/O
97	I/O
98	I/O
99	I/O
100	GND
101	GNDI
102	NC
103	I/O
104	I/O
105	I/O
106	I/O
107	I/O
108	I/O
109	I/O
110	SDI
111	I/O
112	I/O
113	I/O
114	I/O
115	I/O
116	GNDQ

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
237	GND
238	MODE
239	VCCA
240	GND

Figure 46 • VQ80

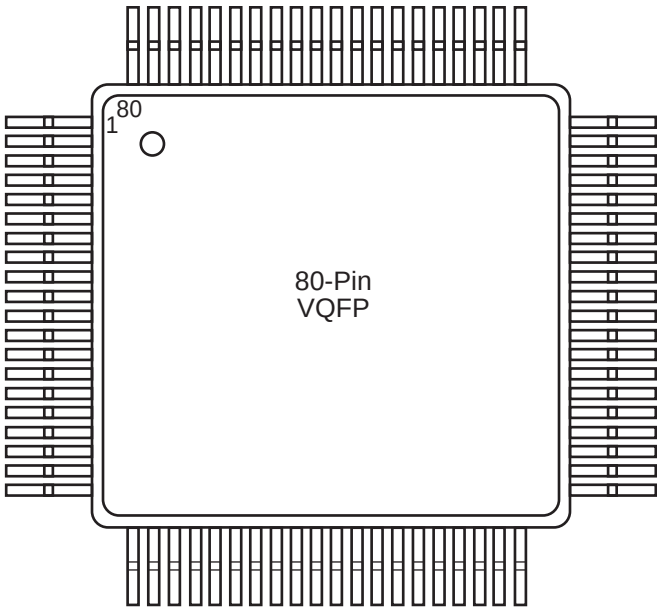


Table 55 • VQ80

VQ80		
Pin Number	A40MX02 Function	A40MX04 Function
1	I/O	I/O
2	NC	I/O
3	NC	I/O
4	NC	I/O
5	I/O	I/O
6	I/O	I/O
7	GND	GND
8	I/O	I/O
9	I/O	I/O
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O

Figure 47 • VQ100

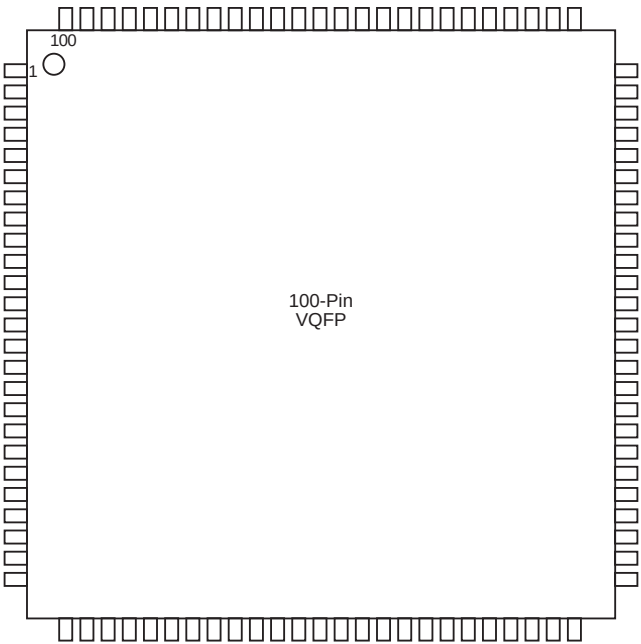


Table 56 • VQ100

VQ100		
Pin Number	A42MX09 Function	A42MX16 Function
1	I/O	I/O
2	MODE	MODE
3	I/O	I/O
4	I/O	I/O
5	I/O	I/O
6	I/O	I/O
7	GND	GND
8	I/O	I/O
9	I/O	I/O
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	VCCA	NC
15	VCCI	VCCI
16	I/O	I/O
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	GND	GND

Table 57 • TQ176

TQ176			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
158	CLKB, I/O	CLKB, I/O	CLKB, I/O
159	I/O	I/O	I/O
160	PRB, I/O	PRB, I/O	PRB, I/O
161	NC	I/O	WD, I/O
162	I/O	I/O	WD, I/O
163	I/O	I/O	I/O
164	I/O	I/O	I/O
165	NC	NC	WD, I/O
166	NC	I/O	WD, I/O
167	I/O	I/O	I/O
168	NC	I/O	I/O
169	I/O	I/O	I/O
170	NC	VCCI	VCCI
171	I/O	I/O	WD, I/O
172	I/O	I/O	WD, I/O
173	NC	I/O	I/O
174	I/O	I/O	I/O
175	DCLK, I/O	DCLK, I/O	DCLK, I/O
176	I/O	I/O	I/O

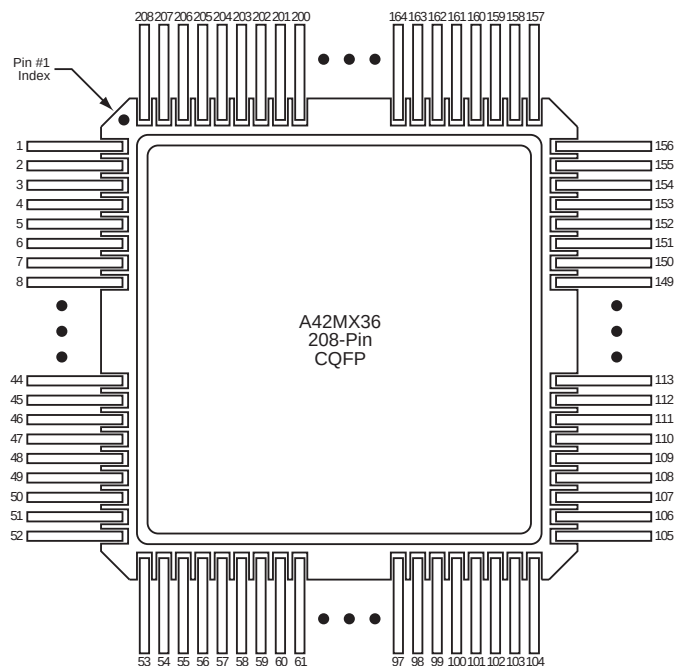
Figure 49 • CQ208

Table 62 • CQ172

99	I/O
100	I/O
101	I/O
102	I/O
103	GND
104	I/O
105	I/O
106	VKS
107	VPP
108	GND
109	VCCI
110	VSV
111	I/O
112	I/O
113	VCC
114	I/O
115	I/O
116	I/O
117	I/O
118	GND
119	I/O
120	I/O
121	I/O
122	I/O
123	GNDI
124	I/O
125	I/O
126	I/O
127	I/O
128	I/O
129	I/O
130	I/O
131	SDI
132	I/O
133	I/O
134	I/O
135	I/O
136	VCCI
137	I/O

Table 62 • CQ172

138	I/O
139	I/O
140	I/O
141	GND
142	I/O
143	I/O
144	I/O
145	I/O
146	I/O
147	I/O
148	PROBA
149	I/O
150	CLKA
151	VCC
152	GND
153	I/O
154	CLKB
155	I/O
156	PROBB
157	I/O
158	I/O
159	I/O
160	I/O
161	GND
162	I/O
163	I/O
164	I/O
165	I/O
166	VCCI
167	I/O
168	I/O
169	I/O
170	I/O
171	DCLK